

**110A, 60V N-CHANNEL POWER MOSFET**

**GENERAL DESCRIPTION**

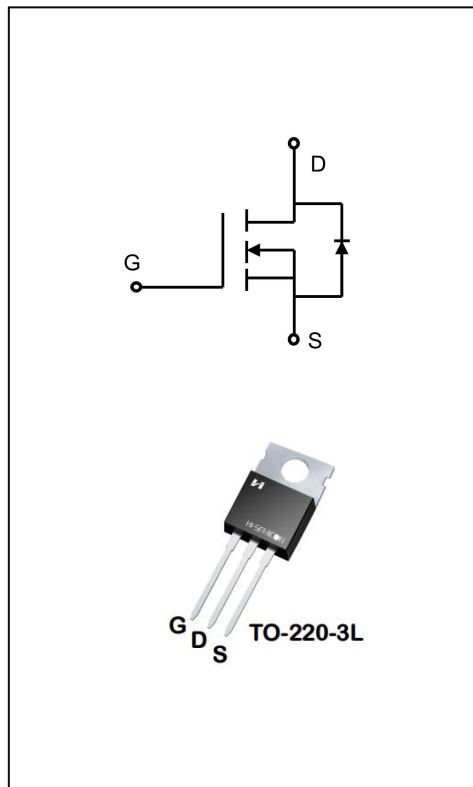
The SFP110N06 uses advanced Process technology and design to provide excellent  $R_{DS(on)}$  with low gate charge. It can be used in a wide variety applications.

**Features**

- ◆  $V_{DS}=60V, I_D=110A$
- ◆  $R_{DS(on)}$   
TYP:  $7.0m\Omega @ V_{GS}=10V, I_D=60A$

**Applications**

- ◆ Power faction correction (PFC)
- ◆ Switched mode power supplies (SMPS)
- ◆ Uninterruptible power supply (UPS)
- ◆ LED lighting power



**ORDERING INFORMATION**

Part No.	Package	Marking	Material	Packing
SFP110N06	TO-220-3L	SFP110N06	Pb Free	Tube

### ABSOLUTE MAXIMUM RATINGS (T<sub>J</sub>=25°C unless otherwise noted)

Characteristics		Symbol	Ratings	Unit
Drain-Source Voltage		V <sub>DS</sub>	60	V
Gate-Source Voltage		V <sub>GS</sub>	±20	V
Drain Current	T <sub>C</sub> = 25°C	I <sub>D</sub>	110	A
	T <sub>C</sub> = 100°C		77	
Drain Current Pulsed(Note 1)		I <sub>DM</sub>	440	A
Power Dissipation(T <sub>C</sub> =25°C) -Derate above 25°C		P <sub>D</sub>	108	W
			0.72	W/°C
Single Pulsed Avalanche Energy (Note 2)		E <sub>AS</sub>	653	mJ
Operation Junction Temperature Range		T <sub>J</sub>	-55~+150	°C
Storage Temperature Range		T <sub>stg</sub>	-55~+150	°C
Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		TL	300	°C

### THERMAL CHARACTERISTICS

Characteristics	Symbol	MAX	Unit
Thermal Resistance, Junction-to-Case	R <sub>θJC</sub>	0.65	°C/W
Thermal Resistance, Junction-to-Ambient	R <sub>θJA</sub>	62	°C/W

### ELECTRICAL CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
<b>Off Characteristics</b>						
Drain -Source Breakdown Voltage	B <sub>VDS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	60	--	--	V
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V	--	--	1.0	uA
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V	--	--	100	nA
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =-20V, V <sub>DS</sub> =0V	--	--	-100	nA
<b>On Characteristics</b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> =250μA	2.0	--	4.0	V
Static Drain- Source On State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =60A	--	7.0	8.0	mΩ
<b>Dynamic Characteristics</b>						
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =25V V <sub>GS</sub> =0V f=1.0MHZ	--	2699	--	pF
Output Capacitance	C <sub>oss</sub>		--	1016	--	
Reverse Transfer Capacitance	C <sub>rss</sub>		--	487	--	
<b>Switching Characteristics</b>						
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> =28V; V <sub>GS</sub> =15V R <sub>G</sub> =25Ω; I <sub>D</sub> =42A	--	52	--	ns
Turn-on Rise Time	t <sub>r</sub>		--	142	--	
Turn-off Delay Time	t <sub>d(off)</sub>		--	355	--	
Turn-off Fall Time	t <sub>f</sub>		--	230	--	

Total Gate Charge	$Q_g$	$V_{DS}=28V, I_D=42A$ $V_{GS}=15V$	--	115	--	nc
Gate-Source Charge	$Q_{gs}$		--	13	--	
Gate-Drain Charge	$Q_{gd}$		--	55	--	

**SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS**

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	$I_S$	Integral Reverse P-N Junction Diode in the MOSFET	--	--	110	A
Pulsed Source Current	$I_{SM}$		--	--	440	
Diode Forward Voltage	$V_{SD}$	$I_S=40A, V_{GS}=0V$	--	--	1.2	V
Reverse Recovery Time	$T_{rr}$	$I_F=180A, V_{GS}=0V,$ $dIF/dt=100A/\mu S$	--	100	--	ns
Reverse Recovery Charge	$Q_{rr}$		--	0.33	--	$\mu C$

1. Pulse width limited by maximum junction temperature
2.  $L=1mH, V_{DD}=50V, R_G=25\Omega$ , starting  $T_J=25^\circ C$
3. Pulse Test: Pulse width  $\leq 300\mu s$ , Duty cycle  $\leq 1\%$
4. Essentially independent of operating temperature

Typical Performance Characteristics

Figure 1. Output Characteristics ( $T_J = 25^\circ\text{C}$ )

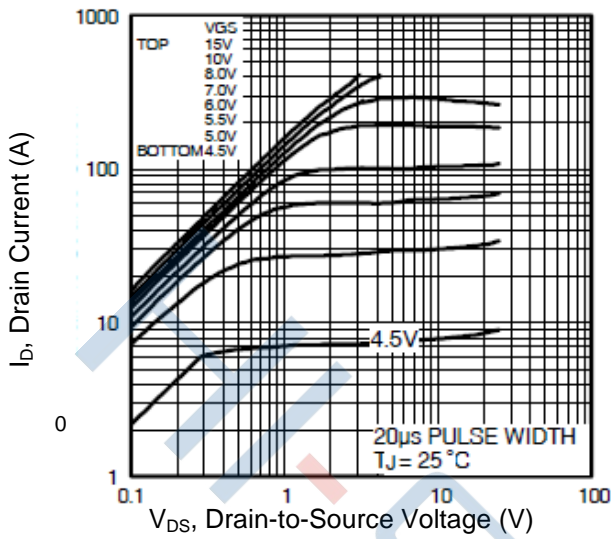


Figure 2. Body Diode Forward Voltage

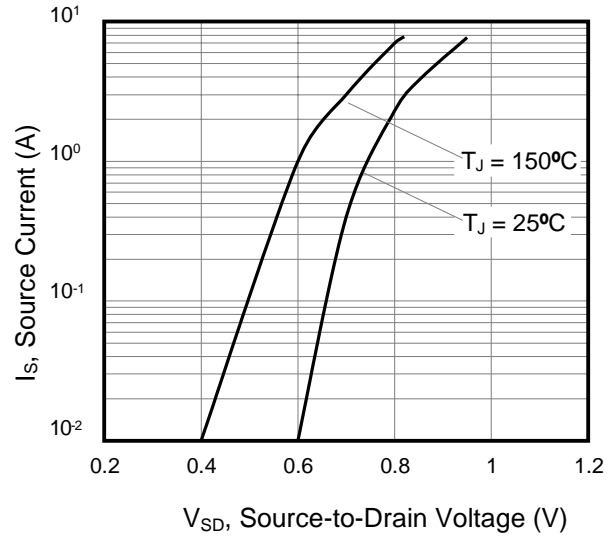


Figure 3. Drain Current vs. Temperature

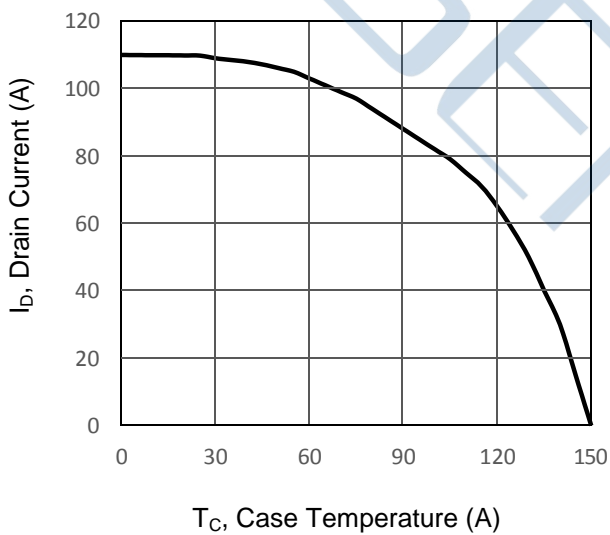


Figure 4.  $BV_{DSS}$  Variation vs. Temperature

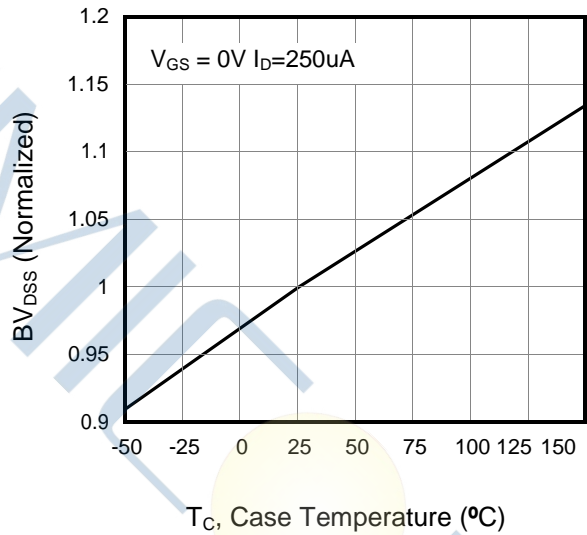


Figure 5. Transfer Characteristics

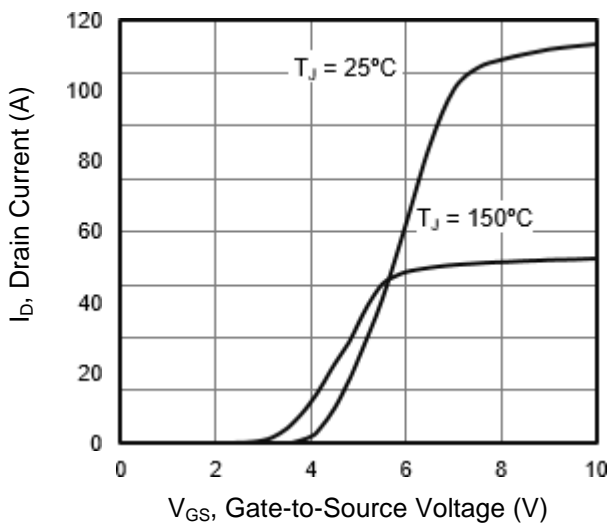
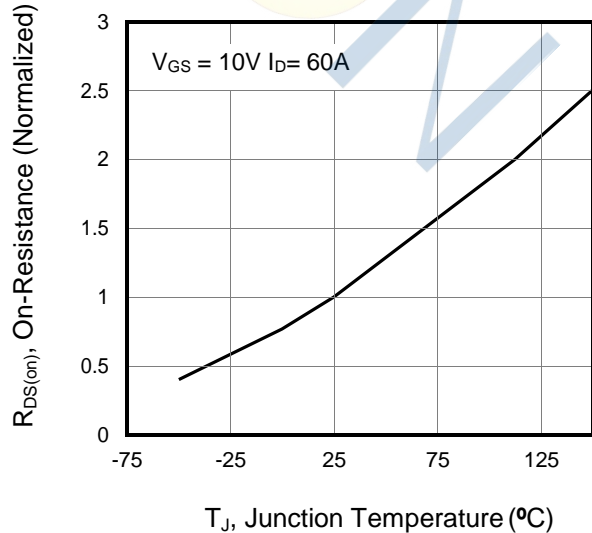


Figure 6. On-Resistance vs. Temperature



Typical Performance Characteristics

Figure 7. Capacitance

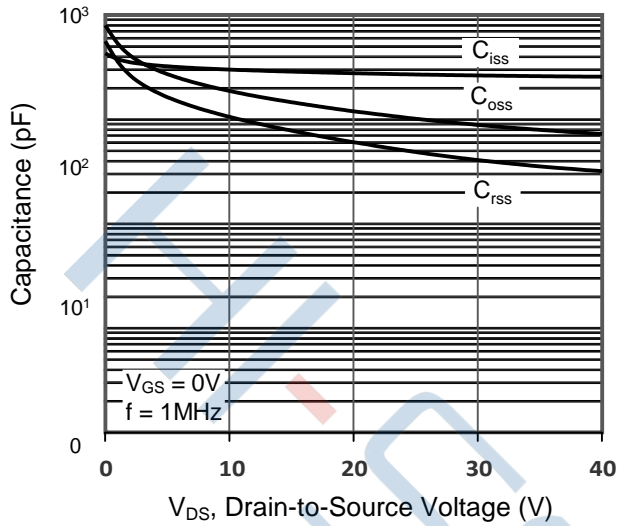


Figure 8. Gate Charge

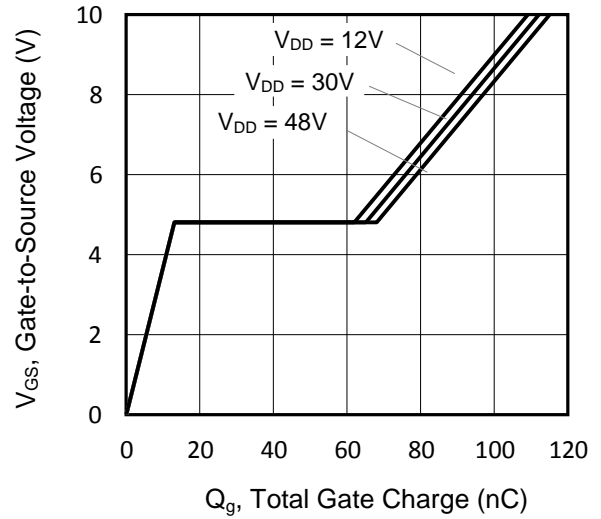
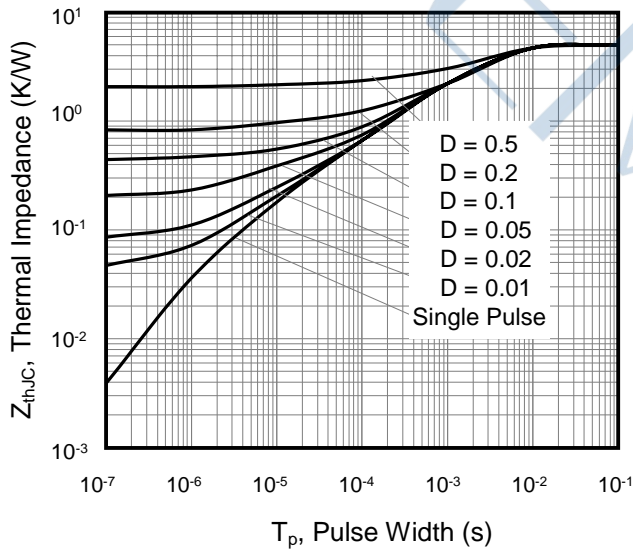


Figure 9. Transient Thermal Impedance TO-220



Test Circuit

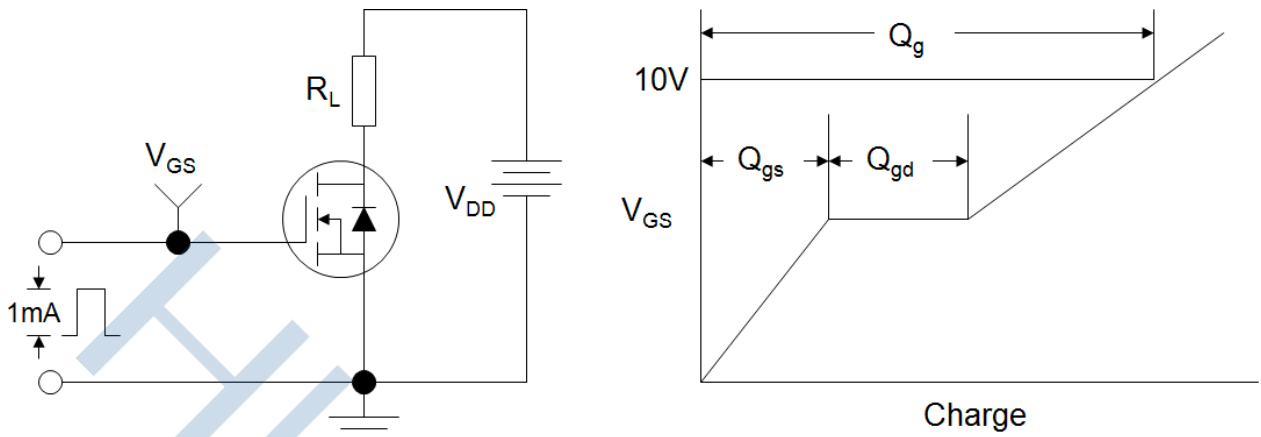


Figure B: Resistive Switching Test Circuit and Waveform

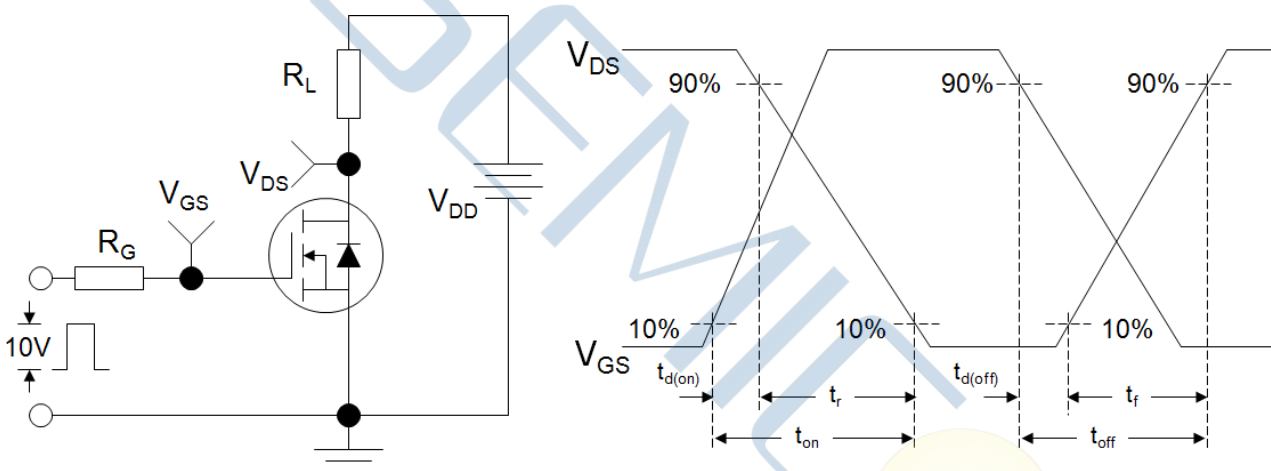
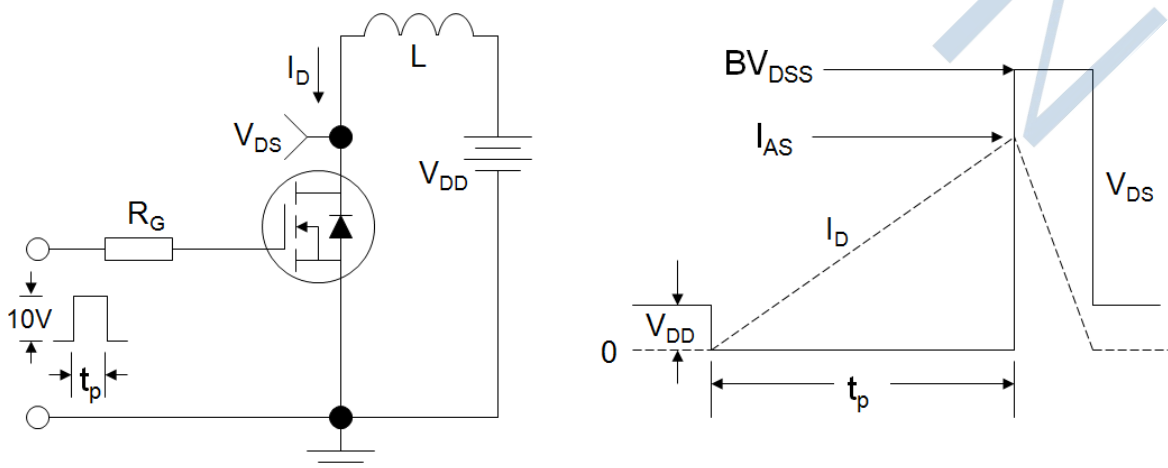
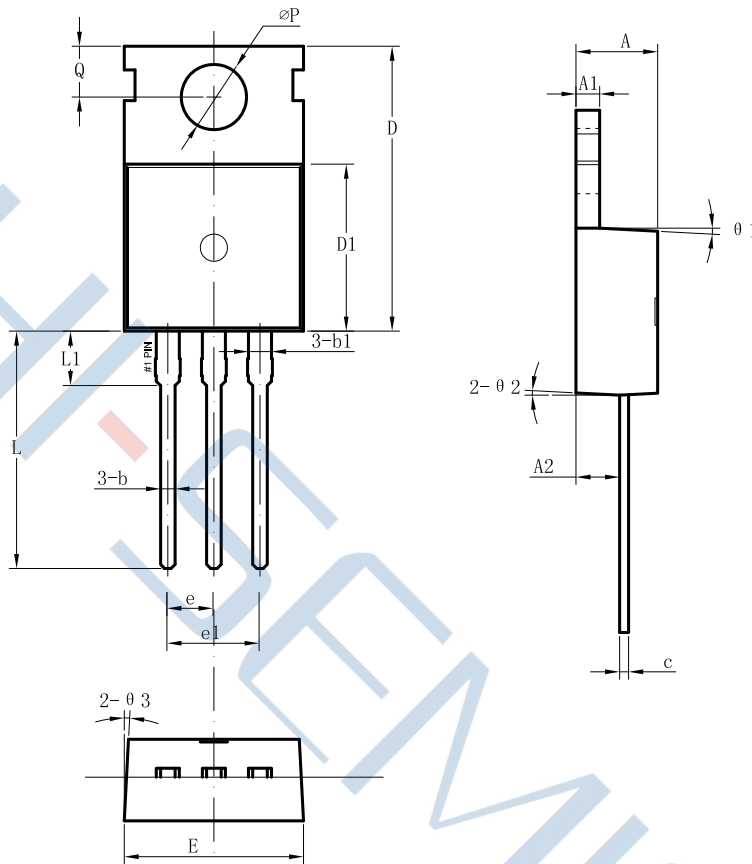


Figure C: Unclamped Inductive Switching Test Circuit and Waveform



Package Dimensions of TO-220-3L

Unit:mm



符号	机械尺寸/mm		
	最小值	典型值	最大值
A	4.30	4.50	4.70
A1	1.25	1.30	1.40
A2	2.20	2.40	2.60
b	0.70	0.80	0.95
b1		1.27	
c	0.40	0.50	0.65
D	15.20	15.70	16.20
D1	9.00	9.20	9.40
E	9.70	10.0	10.10
e		2.54	
e1		5.08	
L	12.60	13.08	13.60
L1		3.00	
φP	3.50	3.60	3.80
Q	2.60	2.80	3.00
θ1		3°	
θ2		3°	
θ3		3°	

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